

# **Burn In Test**

The Burn-In test will expose the DUT (device under test) to harsh conditions: 150°C; relative humidity (RH): 85 rh; current rating: 1A continuous for 1000 hrs. In order to withstand conditions like that, C.C.P. modifies the plating material and core material. C.C.P. splits the socket into two parts: The standard part and the machining part. The standard part is manufactured by insert molding and holds the machining part which is customized according to the customers' IC design and made by CNC. The pins for the burn-in solution use a special material (WJ3) that shows an exceptional hardness and is able to withstand the demanding conditions posed by the Burn-In test.

# Design Concept



Burn in Socket	Specification
IC Size	<15x15 mm²
Min. Pitch	0.3
Body Material	PES (Black)
Housing Material	Ultem2300
Operating Temperature	-55°C~180°C

Pogo Type Burn-in Socket

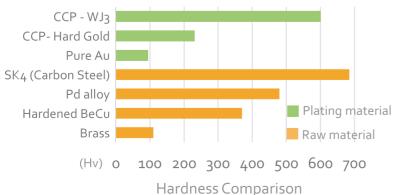
C.C.P. splits the socket into a standard part and a machining part. The standard part is processed by insert molding while the machining part is manufactured by CNC according to IC's size. This shortens the development time and reduces the mold tooling cost. C.C.P. can customize the sockets according to your needs.





Customized part Standard Part Manufactured according to IC size

# Plating / Raw Material



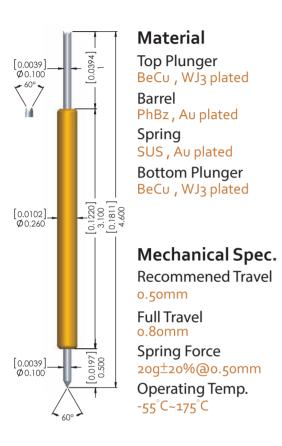
Commonly used in burn in test solution, WJ3 is a special plating material developed by C.C.P. and usually plated on the DUT side plunger. Besides high hardness, WJ3 is able to perform steadily in severe testing environments that reach 150°C for 1000 hours possibly even for 3000 hours.



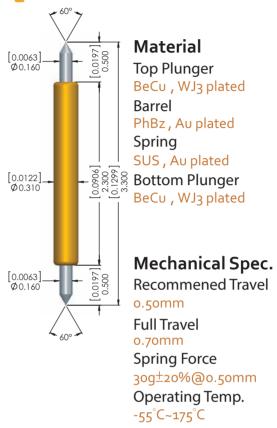
# **Probe Specifications**

Unit:mm; [ ]:in

#### WE1-026FF31-01A0



# WE1-031BB23-01A0



## **Electrical Spec.**

Current Rating 1A continuous Contact Resistance  $<175m\Omega(AVG)$ Characteristic Impedance  $57\Omega$ Insertion Loss -1dB>20GHz Return Loss -20dB@8.38GHz Time Delay 23.4 psec Loop Inductance 1.34 nH Capacitance 0.41pF

# **Electrical Spec.**





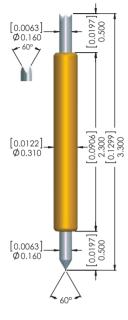
Current Rating 1.5A continuous Contact Resistance <175m $\Omega(AVG)$ Characteristic Impedance  $40.8 \Omega$ Insertion Loss -1dB >20 GHz Return Loss -2odB@ 5.3 GHz Time Delay 15.9 psec Loop Inductance o.65 nH Capacitance 0.39 pF



# **Probe Specifications**

Unit:mm; [ ]:in

#### WE1-031BF23-01A0



#### Material

Top Plunger
BeCu , WJ3 plated
Barrel
PhBz , Au plated
Spring
SUS , Au plated
Bottom Plunger
BeCu , WJ3 plated

#### Mechanical Spec. Recommened Travel

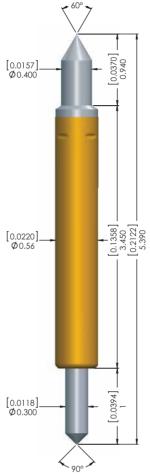
o.5omm

Full Travel
o.7omm

Spring Force

 $3 \text{og} \pm 20\% @ 0.5 \text{omm}$ Operating Temp.  $-55^{\circ}\text{C} \sim 175^{\circ}\text{C}$ 

### **WE3-056BE34-02A0**



#### Material

Top Plunger
BeCu, WJ3 plated
Barrel
Brass, Au plated
Spring
SUS, Au plated
Bottom Plunger
BeCu, WJ3 plated

#### Mechanical Spec.

Recommened Travel o.67mm

Full Travel o.gomm Spring Force

35g±20%@0.67mm Operating Temp.

-55°C~175°C

### Electrical Spec.



Current Rating 1.5A continuous Contact Resistance <175m $\Omega$ (AVG) Characteristic Impedance 33.72 $\Omega$  Insertion Loss -1dB@12.51GHz Return Loss -2odB@2.49GHz Time Delay 17.2 psec Loop Inductance 0.58 nH Capacitance 0.51 pF

### **Electrical Spec.**



Current Rating 5A continuous Contact Resistance  $<75m\Omega(AVG)$ Characteristic Impedance  $32.1\Omega$ Insertion Loss -1dB@7GHzReturn Loss -2odB@1.19GHzTime Delay 29.5psecLoop Inductance 0.95nHCapacitance 0.92pF